

## RELIABILITY DATA

**LT1965 LT3008/09 LT3015 LT3022/29 LT3050/60/80/82/83/85/92 LT3570**

**9/22/2011**

**• OPERATING LIFE TEST**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS <sup>(1)</sup> AT +125°C	NUMBER OF FAILURES <sup>(2)</sup>
SOIC/SOT/MSOP	266	0813	0943	602.70	0
SSOP/TSSOP	77	0941	0941	77.00	0
QFN/DFN	539	0713	0943	539.00	0
HERMETIC	231	1034	1034	616.00	0
	1,113			1,834.70	0

**• PRESSURE COOKER TEST AT 15 PSIG, +121°C**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES
SOIC/SOT/MSOP	3,669	0739	1013	238.45	0
QFN/DFN	655	0739	1013	115.68	0
	4,324			354.13	0

**• TEMP CYCLE FROM -65°C to +150°C**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	1,556	0739	1033	477.80	0
QFN/DFN	682	0739	1013	355.90	0
	2,238			833.70	0

**• THERMAL SHOCK FROM -65°C to +150°C**

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	1,561	0739	1033	691.10	0
QFN/DFN	640	0739	1013	340.30	0
	2,201			1,031.40	0

(1) Assumes Activation Energy = 1.0 Electron Volts

(2) Failure Rate Equivalent to +55°C, 60% Confidence Level = 1.00 FITS

(3) Mean Time Between Failures in Years = 114,576

Note: 1 FIT = 1 Failure in One Billion Hours.